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| Notice of References Cited | Application/Control No. 10/619,707 | Applicant(s)/Patent Under Reexamination PAEK ET AL. | |
| | Examiner Carlos Lopez | Art Unit 1731 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-6,519,974 | 02-2003 | Oh et al. | 65/379 |
| | B | US-5,931,984 | 08-1999 | Drouart et al. | 65/540 |
| | C | US-5,637,130 | 06-1997 | Nagayama et al. | 65/435 |
| | D | US-4,154,592 | 05-1979 | Bailey, Alan C. | 65/424 |
| | E | US-2002/0095955 | 07-2002 | Ball et al. | 65/475 |
| | F | US-2003/0041628 | 03-2003 | Bird et al. | 65/533 |
| | G | US-2004/0089025 | 05-2004 | Kuwahara et al. | 065/382 |
| | H | US-2002/0029591 | 03-2002 | DICKINSON JR. et al. | 65/379 |
| | I | US-2001/0023598 | 09-2001 | Kohmura et al. | 65/377 |
| | J | US-6,543,257 | 04-2003 | Koaizawa et al. | 65/489 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-----------------|----------------|
| | N | JP 06056458 A | 03-1994 | Japan | FUJIMAKI et al. | C03B 37/029 |
| | O | DE 4006839 A1 | 09-1991 | Germany | LYSSON et al. | B01J 19/14 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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